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-	184	percept	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/02 12:03
-	1	percept adj vector$1	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/02 12:05
-	72	linkage adj matrix	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/02 12:12
-	245	artificial adj retina	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/02 12:12
-	271	artificial adj retina$1	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/02 12:12
-	44680	transfer adj function$1	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/02 12:13
-	10	(artificial adj retina$1) and (transfer adj function$1)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/02 12:18
-	396	receptive adj field$1	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/02 12:19
-	4	(artificial adj retina$1) and (receptive adj field$1)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/02 12:41
-	2	percept adj response$1	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/02 13:14
-	7069	point$1 same ((sensor$1 or detector$1) near2 array$1)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/02 14:04
-	1339	((detect$3 or sens$3) near2 point$1) same ((sensor$1 or detector$1) near2 array$1)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/02 14:20
-	1242	((detect$3 or sens$3) near2 (point$1 or spot$1)) with ((sensor$1 or detector$1) near2 array$1)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/02 13:36
-	220520	(location$1 or position$1) near3 (point$1 or spot$1)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/02 13:41

-	508	(((detect$3 or sens$3) near2 (point$1 or spot$1)) with ((sensor$1 or detector$1) near2 array$1)) and ((location$1 or position$1) near3 (point$1 or spot$1))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/02 13:41
-	193	(((detect$3 or sens$3) near2 (point$1 or spot$1)) with ((sensor$1 or detector$1) near2 array$1)) same ((location$1 or position$1) near3 (point$1 or spot$1))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/02 13:41
-	103	(transfer adj function$1) with ((sensor$1 or detector$1) near2 array$1)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/04 14:17
-	16	(impulse adj response) with ((sensor$1 or detector$1) near2 array$1)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/02 14:14
-	6816	((lenslet or microlens$3) adj2 array$1) or (fly$1 adj eye adj lens$2)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/02 15:30
-	0	(((lenslet or microlens$3) adj2 array$1) or (fly$1 adj eye adj lens$2)) with (impulse adj response)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/02 14:17
-	6	(((lenslet or microlens$3) adj2 array$1) or (fly$1 adj eye adj lens$2)) with ((receptive adj field$1) or (transfer adj function$1))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/02 14:17
-	49444	((sensor$1 or detector$1) near2 array$1)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/02 14:20
-	8914	(overlap$4 near3 (field$1 or response$1))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/04 14:12
-	0	((overlap$4 near3 (field$1 or response$1))) same (artificial adj retina$1)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/02 14:22
-	116	((overlap$4 near3 (field$1 or response$1))) same ((((lenslet or microlens$3) adj2 array$1) or (fly$1 adj eye adj lens$2)) or (((sensor$1 or detector$1) near2 array$1)))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/02 14:39
-	1	"2442690".PN.	USPAT	2004/09/02 14:24
-	1	"5196689".PN.	USPAT	2004/09/02 14:25
-	1	"5784156".PN.	USPAT	2004/09/02 14:27
-	13	(feature adj vector$1) same ((((lenslet or microlens$3) adj2 array$1) or (fly$1 adj eye adj lens$2)) or (((sensor$1 or detector$1) near2 array$1)))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/02 14:48
-	1398	(382/181,190,201,323,324).CCLS.	USPAT; US-PGPUB	2004/09/02 14:56
-	21	((382/181,190,201,323,324).CCLS.) and ((receptive adj field$1) or (artificial adj retina$1) or (((lenslet or microlens$3) adj2 array$1) or (fly$1 adj eye adj lens$2)))	USPAT; US-PGPUB	2004/09/02 15:01
-	17	((382/181,190,201,323,324).CCLS.) and ((overlap$4 near3 (field$1 or response$1)))	USPAT; US-PGPUB	2004/09/02 15:08

-	151	(feature adj vector$1) with (covariance or autocovariance)	USPAT; US-PGPUB	2004/09/02 15:08
-	25	((feature adj vector$1) with (covariance or autocovariance)) and ((382/181,190,201,323,324).CCLS.)	USPAT; US-PGPUB	2004/09/02 15:09
-	64	((feature adj vector$1) with (covariance or autocovariance)) and 382/$.ccls.	USPAT; US-PGPUB	2004/09/02 15:29
-	55438	(point or spot) near3 detect$3	USPAT; US-PGPUB	2004/09/02 15:30
-	22197	(detector or sensor) adj array$1	USPAT; US-PGPUB	2004/09/02 16:16
-	4586	((lenslet or microlens$3) adj2 array$1) or (fly$1 adj eye adj lens$2)	USPAT; US-PGPUB	2004/09/02 15:31
-	547	(((detector or sensor) adj array$1) or (((lenslet or microlens$3) adj2 array$1) or (fly$1 adj eye adj lens$2))) with overlap$4	USPAT; US-PGPUB	2004/09/02 15:32
-	9	((((detector or sensor) adj array$1) or (((lenslet or microlens$3) adj2 array$1) or (fly$1 adj eye adj lens$2))) with overlap$4) with response	USPAT; US-PGPUB	2004/09/02 15:32
-	9	((((detector or sensor) adj array$1) or (((lenslet or microlens$3) adj2 array$1) or (fly$1 adj eye adj lens$2))) with overlap$4) with response$1	USPAT; US-PGPUB	2004/09/02 15:32
-	122	((((detector or sensor) adj array$1) or (((lenslet or microlens$3) adj2 array$1) or (fly$1 adj eye adj lens$2))) with overlap$4) and ((point or spot) near3 detect$3)	USPAT; US-PGPUB	2004/09/02 15:33
-	20	(((((detector or sensor) adj array$1) or (((lenslet or microlens$3) adj2 array$1) or (fly$1 adj eye adj lens$2))) with overlap$4) and ((point or spot) near3 detect$3)) and 382/$.ccls.	USPAT; US-PGPUB	2004/09/02 15:33
-	29	(((((detector or sensor) adj array$1) or (((lenslet or microlens$3) adj2 array$1) or (fly$1 adj eye adj lens$2))) with overlap$4) with response$1) or ((((((detector or sensor) adj array$1) or (((lenslet or microlens$3) adj2 array$1) or (fly$1 adj eye adj lens$2))) with overlap$4) and ((point or spot) near3 detect$3)) and 382/$.ccls.)	USPAT; US-PGPUB	2004/09/02 15:40
-	46	dot adj detector$1	USPAT; US-PGPUB	2004/09/02 15:43
-	139	kronecker adj product	USPAT; US-PGPUB	2004/09/02 15:44
-	1	(kronecker adj product) and 382/100,181,190,201,323,324.ccls.	USPAT; US-PGPUB	2004/09/02 15:45
-	1	(tensor adj product) and 382/100,181,190,201,323,324.ccls.	USPAT; US-PGPUB	2004/09/02 15:57
-	1	("5077790").PN.	USPAT; US-PGPUB	2004/09/02 15:58
-	0	("wo9841044-$.did.").PN.	EPO; DERWENT	2004/09/02 15:59
-	0	("wo-9841044-$.did.").PN.	EPO; DERWENT	2004/09/02 15:59
-	0	("wo-9841044-$").PN.	EPO; DERWENT	2004/09/02 15:59
-	0	("wo9841044$").PN.	EPO; DERWENT	2004/09/02 15:59
-	0	("wo9841044").PN.	EPO; DERWENT	2004/09/02 15:59
-	1	("5553315").PN.	EPO; DERWENT	2004/09/02 16:00
-	1	("5301019").PN.	EPO; DERWENT	2004/09/02 16:00
-	529	overlap$4 near3 views	USPAT; US-PGPUB	2004/09/02 16:16
-	22979	(detector or sensor) adj (array$1 or matrix)	USPAT; US-PGPUB	2004/09/02 16:17
-	2	(overlap$4 near3 views) same ((detector or sensor) adj (array$1 or matrix))	USPAT; US-PGPUB	2004/09/02 16:17

-	33	(overlap$4 near3 views) and ((detector or sensor) adj (array$1 or matrix))	USPAT; US-PGPUB	2004/09/02 16:17
-	452	(382/195,205).CCLS.	USPAT; US-PGPUB	2004/09/04 14:01
-	0	((382/195,205).CCLS.) and precept	USPAT; US-PGPUB	2004/09/04 14:01
-	0	((382/195,205).CCLS.) and percept	USPAT; US-PGPUB	2004/09/04 14:01
-	4	((382/195,205).CCLS.) and linkage	USPAT; US-PGPUB	2004/09/04 14:11
-	9	((382/195,205).CCLS.) and (overlap$4 near3 (field$1 or response$1 or view$1 or receptive))	USPAT; US-PGPUB	2004/09/04 14:12
-	88	(transfer adj function$1) with ((sensor$1 or detector$1) near2 array$1)	USPAT; US-PGPUB	2004/09/04 14:18
-	95	(transfer adj function$1) with ((sensor$1 or detector$1) near2 (array$1 or matrix))	USPAT; US-PGPUB	2004/09/04 14:18
-	7044	((transfer adj function$1) with ((sensor$1 or detector$1) near2 (array$1 or matrix))) ane ((382/195,205).CCLS.)	USPAT; US-PGPUB	2004/09/04 14:18
-	0	((transfer adj function$1) with ((sensor$1 or detector$1) near2 (array$1 or matrix))) and ((382/195,205).CCLS.)	USPAT; US-PGPUB	2004/09/04 14:18

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```
(((lenslet <or> microlens*)
<near/2> array) <or> (fly*
eye lens)) <and> (response
<or> (transfer function))
```

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```
spot <near/8> ((detector <or>
sensor) <near/2> array)
```

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```
point <near/8> ((detector
<or> sensor) <near/2> array)
```

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```
(receptive field) <and>
(sensor <or> detector <or>
retina)
```

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(artificial retina)

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3) Limit the results by selecting Search Options.
4) Click Search. See Search Examples

```
((detector <or> sensor)
<near/2> (array or matrix))
<and> overlap*
```

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(feature vector) <and> linkage Search

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